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APPLICATION NO.	F	ILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/928,430	-	08/14/2001	Kazuyuki Nitta	2001-1143A	8121
513	7590	05/05/2003			
	•	ND & PONACK, I	EXAMINER		
2033 K STR SUITE 800		•	LEE, SIN J		
WASHINGTON, DC 20006-1021				ART UNIT	PAPER NUMBER
				1752	

DATE MAILED: 05/05/2003

Please find below and/or attached an Office communication concerning this application or proceeding.

	Acknowledgment is made of a claim for domes			nal annlication)				
* 5	application from the International B See the attached detailed Office action for a lis							
3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).								
	2. Certified copies of the priority documents have been received in Application No							
	1. Certified copies of the priority documen	nts have been rece	ived.					
a)	⊠ All b) Some * c) None of:							
13)⊠	Acknowledgment is made of a claim for foreign	gn priority under 35	U.S.C. § 119(a)-(d) or (f).					
Priority (under 35 U.S.C. §§ 119 and 120							
12)	The oath or declaration is objected to by the E	xaminer.						
	If approved, corrected drawings are required in re	eply to this Office ac	ion.					
11) ☐ The proposed drawing correction filed on is: a) ☐ approved b) ☐ disapproved by the Examiner.								
	Applicant may not request that any objection to t	he drawing(s) be hel	d in abeyance. See 37 CFR 1.85(a).				
10)□	The drawing(s) filed on is/are: a)☐ acco	epted or b)⊡ object	ed to by the Examiner.					
9)□	The specification is objected to by the Examin	er.						
	ion Papers	·						
8)	Claim(s) are subject to restriction and/	or election require	ment.					
7)								
6)⊠	Claim(s) 1 and 5-12 is/are rejected.							
	Claim(s) is/are allowed.							
	4a) Of the above claim(s) is/are withdrawn from consideration.							
4)⊠	Claim(s) 1 and 5-12 is/are pending in the app	plication.						
Disposit	closed in accordance with the practice unde ion of Claims	r <i>⊏x par</i> te Quayle,	1935 C.D. 11, 453 O.G. 213.					
3)□	Since this application is in condition for allow			the merits is				
2a)□	This action is FINAL . 2b)⊠ T	his action is non-fi	nal.					
1) 🗆	Responsive to communication(s) filed on 06	February 2003 .						
- Any i	re to reply within the set or extended period for reply will, by staturely received by the Office later than three months after the mailined patent term adjustment. See 37 CFR 1.704(b).							
- If NC	period for reply specified above is less than thiny (30) days, a re o period for reply is specified above, the maximum statutory period are to reply within the set or extended period for reply will, by statu	will apply and will expire	SIX (6) MONTHS from the mailing date of th					
after	nsions of time may be available under the provisions of 37 CFR is SIX (6) MONTHS from the mailing date of this communication. period for reply specified above is less than thirty (30) days, a rej			melv.				
	MAILING DATE OF THIS COMMUNICATION. nsions of time may be available under the provisions of 37 CFR 1.		ver, may a reply be timely filed					
	ORTENED STATUTORY PERIOD FOR REPI	LY IS SET TO EXF	PIRE 3 MONTH(S) FROM					
Period fo	The MAILING DATE of this communication ap or Reply	pears on the cover	sneet with the correspondence	address				
•	The MAIL INO DATE of this	Rosemary E. Asl		addrass				
	Office Action Summary	Examiner	Art Unit					
	Office Action Summan	09/928,430	NITTA ET AL.					
1				$\mathcal{O}_{\mathcal{I}}$				

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DETAILED ACTION

Claim Rejections - 35 USC § 103

1. The text of those sections of Title 35, U.S. Code not included in this action can be found in a prior Office action.

2. Claims 11 and 12 are rejected under 35 U.S.C. 103(a) as being unpatentable over Watanabe in view of Ohsawa and further in view of Blakeney for the reasons stated in paragraphs 3 and 4 in paper no. 4. This rejection is maintained from the prior office action.

Response to Arguments

3. Applicant's arguments filed February 6, 2003 have been fully considered but they are not persuasive.

Applicant argues that the rejection is based on inherency, however, this is not the case.

As stated in the prior rejection Blakeney teaches the purpose of a post development heating step is to increase adhesion and chemical resistance of the resist composition and to improve the resist thermal flow temperature. As stated in Blakeney columns 2 and 10:

Post development cure treatments of the resist, such as DUV cure or stepped-up post baking cycles are sometimes necessary to apply to improve the resist thermal flow temperature.

A post-development heat treatment or bake may then be employed to increase the coating's adhesion and chemical resistance to etching solutions and other substances.

Thus, the post development step aids in the overall pattern stability of the patterned photoresist composition.

4. Applicant's arguments with respect to claims 1,5-10 have been considered but are moot in view of the new ground(s) of rejection.

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5. Claims 1,5-10 are rejected under 35 U.S.C. 103(a) as being unpatentable over Oomori et al U.S. patent no. 5,976,760 in view of Watanabe et al U.S. patent no. 5,876,900 cited in the prior office action.

As shown in example 1 below Oomori teaches a positive photoresist composition comprising 100 parts by weight (pbw) of a polymer mixture containing 25 pbw of a polyhydroxystyrene having phenolic hydrogens replaced with a tertiary alkoxycarbonyl group (applicant's A2) and 75 pbw of polyhydroxystyrene having phenolic hydrogens replaced with an alkoxyalkyl group (applicant's A1). The composition comprises 3 pbw of an oxime sulfonate photoacid generator, 0.06 pbw of the amine compound triethylamine and 0.06 pbw of the carboxylic acid salicylic acid.

EXAMPLE 1

A chemical-sensitization positive-working resist composition was prepared by dissolving, in 400 parts by weight of propyleneglycol monomethyl ether acetate, 25 parts by weight of a first polyhydroxystyrene resin having a weightaverage molecular weight of 12000 with a molecular weight distribution M_w:M_x of 4.6, which was substituted by tertbutyloxycarbonyl groups for 39% of the hydroxyl groups, 75 parts by weight of a second polyhydroxystyrene resin having a weight-average molecular weight of 12000 with a molecular weight distribution M, :M, of 4.6, which was substituted by ethoxyethyl groups for 39% of the hydroxyl groups, 3 parts by weight of the oximesulfonate compound prepared in Preparation 1 described above, i.e. α-(1naphthylsulfonyloxyimino)-4-methoxybenzyl cyanide, as the acid-generating agent, 0.06 part by weight of triethylamine and 0.06 part by weight of salicylic acid followed by filtration of the solution through a membrane filter of 0.2 μ m pore diameter.

Oomori does not teach the positive photoresist composition has a polyvinyl ether as claimed.

As stated in the prior office action Watanabe teaches a positive photoresist composition comprising a polyhydroxystyrene polymer having phenolic hydrogens replaced with acid labile groups, a photoacid generator, an amine and a polyvinyl ether. Watanabe teaches the polyvinyl ether is used in the composition for the purpose of dissolution control (col. 2, line 1) and as stated in col. 3, lines 12-20 below.

The resist composition not only has an increased dissolution contrast owing to the function of an acid labile group contained in the base resin of formula (1) and the function of a vinyl ether group capable of chemically converting into an acid labile group through heat cross-linking, but is also improved in heat resistance during etching because the crosslinked structure is maintained in unexposed areas.

Thus, it would have been obvious to one of ordinary skill in the art to add a polyvinyl ether compound to the photoresist composition of Oomori with a reasonable expectation of obtaining a chemically amplified positive resist composition having improved performance and improved heat resistance upon etching because Watanabe teaches a composition having the combination of a polyhydroxystyrene having acid labile groups and a polyvinyl ether gives these results (col. 3, lines 36-40).

As to using a tertiary alkanol amine as in claim 10 Watanabe teaches the exemplified triethylamine is equivalent to triethanolamine and thus an obvious alternative reagent in the composition (col. 24, lines 27-31).

Preferred among others are triethylamine, N,N-dimethylaniline, N-methylpyrrolidone, pyridine, quinoline, nicotinic acid, triethanolamine, piperidine ethanol, N,N-dimethylacetamide, and succinimide.

6. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Rosemary E. Ashton whose telephone number is 308-2057. The

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examiner works a flexible work schedule and can normally be reached M-F between 10:00 am and 5:00 pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Janet Baxter can be reached on 308-2303. The fax phone numbers for the organization where this application or proceeding is assigned are 703-872-9310 for regular communications and 703-872-9311 for After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is 703-308-0661.

depla.

Rosemary E. Ashton Primary Examiner Art Unit 1752

rea April 30, 2003 ROSEMARY ASHTON PRIMARY EXAMINER